

Teodor Gotszalk

List of Publications by Year in descending order

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Version: 2024-02-01

38
papers

278
citations

1040056

9
h-index

996975

15
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38
all docs

38
docs citations

38
times ranked

376
citing authors

#	ARTICLE	IF	CITATIONS
1	Calibration and examination of piezoresistive Wheatstone bridge cantilevers for scanning probe microscopy. <i>Ultramicroscopy</i> , 2003, 97, 385-389.	1.9	30
2	Dielectric Barrier Discharge Ionization in Characterization of Organic Compounds Separated on Thin-Layer Chromatography Plates. <i>PLoS ONE</i> , 2014, 9, e106088.	2.5	20
3	Application of quartz tuning forks for detection of endotoxins and Gram-negative bacterial cells by monitoring of Limulus Amebocyte Lysate coagulation. <i>Biosensors and Bioelectronics</i> , 2014, 58, 132-137.	10.1	18
4	Fabrication and characterization of boron-doped nanocrystalline diamond-coated MEMS probes. <i>Applied Physics A: Materials Science and Processing</i> , 2016, 122, 1.	2.3	18
5	Optimal Design of Electromagnetically Actuated MEMS Cantilevers. <i>Sensors</i> , 2018, 18, 2533.	3.8	15
6	FAPA mass spectrometry of designer drugs. <i>Talanta</i> , 2016, 146, 29-33.	5.5	14
7	Investigation of multi-junction solar cells using electrostatic force microscopy methods. <i>Ultramicroscopy</i> , 2014, 141, 1-8.	1.9	13
8	Electrochemical generation of selegiline metabolites coupled to mass spectrometry. <i>Journal of Chromatography A</i> , 2015, 1389, 96-103.	3.7	13
9	Scanning probe microscopy investigations of the electrical properties of chemical vapor deposited graphene grown on a 6H-SiC substrate. <i>Micron</i> , 2015, 68, 17-22.	2.2	11
10	Heat assisted sample introduction and determination of cannabinoids by dielectric barrier discharge ionization mass spectrometry. <i>International Journal of Mass Spectrometry</i> , 2015, 386, 32-36.	1.5	10
11	Self-supporting graphene films and their applications. <i>IET Circuits, Devices and Systems</i> , 2015, 9, 420-427.	1.4	9
12	Contact atomic force microscopy using piezoresistive cantilevers in load force modulation mode. <i>Ultramicroscopy</i> , 2018, 184, 199-208.	1.9	9
13	Electromagnetic cantilever reference for the calibration of optical nanodisplacement systems. <i>Sensors and Actuators A: Physical</i> , 2018, 282, 149-156.	4.1	9
14	Stable Field Electron Emission and Plasma Illumination from Boron and Nitrogen Co-doped Edge-rich Diamond-enhanced Carbon Nanowalls. <i>Advanced Materials Interfaces</i> , 2021, 8, 2100464.	3.7	9
15	Focused ion beam milling and deposition techniques in validation of mass change value and position determination method for micro and nanomechanical sensors. <i>Journal of Applied Physics</i> , 2012, 112, .	2.5	7
16	Piezoresistive cantilever working in a shear force mode for in situ characterization of exposed micro- and nanostructures. <i>Measurement Science and Technology</i> , 2014, 25, 044018.	2.6	7
17	Investigation of thermal effects in through-silicon vias using scanning thermal microscopy. <i>Micron</i> , 2014, 66, 63-68.	2.2	7
18	Technology of thermally driven and magnetototively detected MEMS microbridges. <i>Sensors and Actuators A: Physical</i> , 2016, 240, 17-22.	4.1	7

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19	New design of the cantilevers for radiation pressure investigations. <i>Microelectronic Engineering</i> , 2018, 201, 10-15.	2.4	7
20	Origin and anomalous behavior of dominant defects in 4H-SiC studied by conventional and Laplace deep level transient spectroscopy. <i>Journal of Applied Physics</i> , 2020, 127, .	2.5	7
21	Carrier density distribution in silicon nanowires investigated by scanning thermal microscopy and Kelvin probe force microscopy. <i>Micron</i> , 2015, 79, 93-100.	2.2	6
22	Light Extraction From Scintillating Crystals Enhanced by Photonic Crystal Structures Patterned by Focused Ion Beam. <i>IEEE Transactions on Nuclear Science</i> , 2016, 63, 644-648.	2.0	6
23	Investigations of mechanical properties of microfabricated resonators using atomic force microscopy related techniques. <i>Microelectronic Engineering</i> , 2014, 119, 164-168.	2.4	5
24	Influence of B/N co-doping on electrical and photoluminescence properties of CVD grown homoepitaxial diamond films. <i>Nanotechnology</i> , 2022, 33, 125603.	2.6	5
25	Combined Shear Force-Tunneling Microscope with Interferometric Tip Oscillation Detection for Local Surface Investigation and Oxidation. , 2006, , 144-156.		3
26	Force Spectroscopy with Quantitative On-Cantilever Force Control. <i>Proceedings (mdpi)</i> , 2018, 2, 915.	0.2	2
27	Multifrequency Kelvin probe force microscopy on self assembled molecular layers and quantitative assessment of imagesâ€™ quality. <i>Ultramicroscopy</i> , 2018, 194, 100-107.	1.9	2
28	MEMS displacement generator for atomic force microscopy metrology. <i>Measurement Science and Technology</i> , 2021, 32, 065903.	2.6	2
29	Photon force microelectromechanical system cantilever combined with a fibre optic system as a measurement technique for optomechanical studies. <i>Measurement Science and Technology</i> , 2022, 33, 027001.	2.6	2
30	Fabrication and metrology of electromagnetically actuated microcantilever arrays for biochemical sensing. , 2012, , .		1
31	New approach for a multi-cantilever arrays sensor system with advanced MOEMS readout. , 2016, , .		1
32	Metrological 2iOF fibre-optic system for position and displacement measurement with 31 pm resolution. <i>Review of Scientific Instruments</i> , 2018, 89, 045001.	1.3	1
33	Mechanical Impedance Analysis of a Novel MEMS Photon Force Sensor. <i>Proceedings (mdpi)</i> , 2018, 2, 921.	0.2	1
34	Modification and Characterization of Metallized Tips for Scanning Probe Microscopy. <i>Praktische Metallographie/Practical Metallography</i> , 2007, 44, 451-463.	0.3	1
35	Efficient broken line fitting procedure for analysis of force spectroscopy curves in chemical force microscopy. <i>Journal of Applied Physics</i> , 2013, 114, 064310.	2.5	0
36	Quality factor and resonant frequency measurement by ARMA process identification of randomly excited MEMS/NEMS cantilever. , 2014, , .		0

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37	Quartz tuning fork mass change sensing for FIB/SEM technology. <i>Micron</i> , 2020, 129, 102792.	2.2	0
38	Analysis of the electrolytically polished skeletal dentures surfaces using various nano- and microscopic technologies. <i>Acta of Bioengineering and Biomechanics</i> , 2019, 21, 123-129.	0.4	0